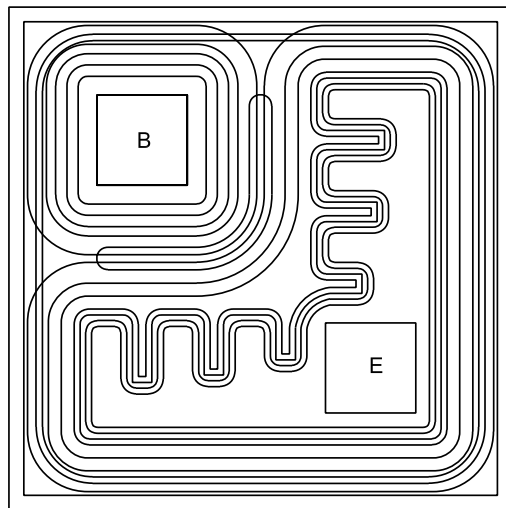


**PROCESS DETAILS**

Process	EPITAXIAL PLANAR
Die Size	27 x 27 MILS
Die Thickness	7.1 MILS
Base Bonding Pad Area	4.2 x 4.2 MILS
Emitter Bonding Pad Area	4.3 x 4.3 MILS
Top Side Metalization	Al - 30,000Å
Back Side Metalization	Au - 13,000Å

**GEOMETRY**



BACKSIDE COLLECTOR

R0

**GROSS DIE PER 4 INCH WAFER**

15,980

**PRINCIPAL DEVICE TYPES**

CMPTA29

CZTA29

MPSA29

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R0 (20 -January 2006)